

RELIABILITY REPORT
FOR MAX6384LT16D1+
(MAX6381-MAX6390)
PLASTIC ENCAPSULATED DEVICES

January 22, 2009

MAXIM INTEGRATED PRODUCTS

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Approved by
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Quality Assurance
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Conclusion

The MAX6384LT16D1+ successfully meets the quality and reliability standards required of all Maxim products. In addition, Maxim's continuous reliability monitoring program ensures that all outgoing product will continue to meet Maxim's quality and reliability standards.

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I. Device Description

A. General

The MAX6381-MAX6390 microprocessor (μ P) supervisory circuits monitor power-supply voltages from +1.8V to +5.0V while consuming only 3 μ A of supply current at +1.8V. Whenever VCC falls below the factory-set reset thresholds, the reset output asserts and remains asserted for a minimum reset timeout period after VCC rises above the reset threshold. Reset thresholds are available from +1.58V to +4.63V, in approximately 100mV increments. Seven minimum reset timeout delays ranging from 1ms to 1200ms are available. The MAX6381/MAX6384/MAX6387 have a push-pull active-low reset output. The MAX6382/MAX6385/MAX6388 have a push-pull active-high reset output, and the MAX6383/MAX6386/MAX6389/MAX6390 have an open-drain active-low reset output. The MAX6384/MAX6385/MAX6386 also feature a debounced manual reset input (with internal pullup resistor). The MAX6387/MAX6388/MAX6389 have an auxiliary input for monitoring a second voltage. The MAX6390 offers a manual reset input with a longer VCC reset timeout period (1120ms or 1200ms) and a shorter manual reset timeout (140ms or 150ms). The MAX6381/MAX6382/MAX6383 are available in 3-pin SC70 and 6-pin μ DFN packages and the MAX6384-MAX6390 are available in 4-pin SC70 and 6-pin μ DFN packages.

II. Manufacturing Information

A. Description/Function:	SC70/ μ DFN, Single/Dual Low-Voltage, Low-Power μ P Reset Circuits
B. Process:	B8
C. Number of Device Transistors:	
D. Fabrication Location:	Texas
E. Assembly Location:	Hana Thailand
F. Date of Initial Production:	October 22, 2000

III. Packaging Information

A. Package Type:	6-pin uDFN
B. Lead Frame:	Substrate
C. Lead Finish:	Gold
D. Die Attach:	Non-conductive Epoxy
E. Bondwire:	Gold (1 mil dia.)
F. Mold Material:	Epoxy with silica filler
G. Assembly Diagram:	#05-9000-2094
H. Flammability Rating:	Class UL94-V0
I. Classification of Moisture Sensitivity per JEDEC standard J-STD-020-C	Level 1
J. Multi Layer Theta Ja:	477°C/W

IV. Die Information

A. Dimensions:	31 X 30 mils
B. Passivation:	$\text{Si}_3\text{N}_4/\text{SiO}_2$ (Silicon nitride/ Silicon dioxide)
C. Interconnect:	Aluminum/Si (Si = 1%)
D. Backside Metallization:	None
E. Minimum Metal Width:	0.8 microns (as drawn)
F. Minimum Metal Spacing:	0.8 microns (as drawn)
G. Bondpad Dimensions:	5 mil. Sq.
H. Isolation Dielectric:	SiO_2
I. Die Separation Method:	Wafer Saw

V. Quality Assurance Information

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|-----------------------------------|---|
| A. Quality Assurance Contacts: | Ken Wendel (Director, Reliability Engineering)
Bryan Preeshl (Managing Director of QA) |
| B. Outgoing Inspection Level: | 0.1% for all electrical parameters guaranteed by the Datasheet.
0.1% For all Visual Defects. |
| C. Observed Outgoing Defect Rate: | < 50 ppm |
| D. Sampling Plan: | Mil-Std-105D |

VI. Reliability Evaluation
A. Accelerated Life Test

The results of the 135°C biased (static) life test are shown in Table 1. Using these results, the Failure Rate (λ) is calculated as follows:

$$\lambda = \frac{1}{\text{MTTF}} = \frac{1.83}{192 \times 4340 \times 80 \times 2} \quad (\text{Chi square value for MTTF upper limit})$$

(where 4340 = Temperature Acceleration factor assuming an activation energy of 0.8eV)

$$\lambda = 13.4 \times 10^{-9}$$

$$\lambda = 13.4 \text{ F.I.T. (60\% confidence level @ 25°C)}$$

The following failure rate represents data collected from Maxim's reliability monitor program. Maxim performs quarterly 1000 hour life test monitors on its processes. This data is published in the Product Reliability Report found at <http://www.maxim-ic.com/>. Current monitor data for the B8 Process results in a FIT Rate of 2.71 @ 25C and 17.30 @ 55C (0.8 eV, 60% UCL)

B. Moisture Resistance Tests

The industry standard 85°C/85%RH or HAST testing is monitored per device process once a quarter.

C. E.S.D. and Latch-Up Testing

The MS58 die type has been found to have all pins able to withstand a HBM transient pulse of +/-1500 V per Mil-Std 883 Method 3015.7. Latch-Up testing has shown that this device withstands a current of +/-250 mA.

Table 1
Reliability Evaluation Test Results

MAX6384LT16D1+

TEST ITEM	TEST CONDITION	FAILURE IDENTIFICATION	SAMPLE SIZE	NUMBER OF FAILURES
Static Life Test (Note 1)	Ta = 135°C Biased Time = 192 hrs.	DC Parameters & functionality	80	0
Moisture Testing (Note 2) 85/85	Ta = 85°C RH = 85% Biased Time = 1000hrs.	DC Parameters & functionality	77	0
Mechanical Stress (Note 2) Temperature Cycle	-55°C/125°C 1000 Cycles Method 1010	DC Parameters & functionality	77	0

Note 1: Life Test Data may represent plastic DIP qualification lots.

Note 2: Generic Package/Process data